

(b) (7)(C), (b) (7)(D)

22

Examiner

Applicant(s)/Patent under Reexamination

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Art Unit	
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SEARCHED			
Class	Subclass	Date	Examiner
331	36C 34, 16	7-4-66	m
11	177V		
	179		
	177R		
360	51		
710	1		
375	376		
360	51		
341	63		
340	536		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

[illegible]